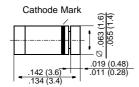
LL4448

Small Signal Diodes

MiniMELF



Dimensions in inches and (millimeters)

FEATURES

- ♦ Silicon Epitaxial Planar Diode
- Fast switching diode in MiniMELF case especially suited for automatic insertion.
- ◆ This diode is also available in other case styles including: the DO-35 case with the type designation 1N4448, the SOD-123 case with the type designation 1N4448W, and the SOT-23 case with the type designation IMBD4448.

MECHANICAL DATA

Case: MiniMELF Glass Case (SOD-80)

Weight: approx. 0.05 g

MAXIMUM RATINGS AND ELECTRICAL CHARACTERISTICS

Ratings at 25 °C ambient temperature unless otherwise specified

	Symbol	Value	Unit
Reverse Voltage	V _R	75	V
Peak Reverse Voltage	V _{RM}	100	V
Rectified Current (Average) Half Wave Rectification with Resist. Load at T_{amb} = 25 °C and f \geq 50 Hz	I ₀	150 ¹⁾	mA
Surge Forward Current at t < 1 s and T _j = 25 °C	I _{FSM}	500	mA
Power Dissipation at T _{amb} = 25 °C	P _{tot}	500 ¹⁾	mW
Junction Temperature	Tj	175	°C
Storage Temperature Range	T _S	-65 to +175	°C
1) Valid provided that electrodes are kept at ambient tem	perature.		

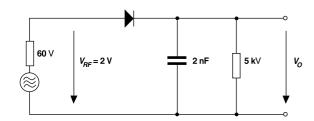
LL4448

ELECTRICAL CHARACTERISTICS

Ratings at 25 °C ambient temperature unless otherwise specified

	Symbol	Min.	Тур.	Max.	Unit
Forward Voltage at I _F = 5 mA at I _F = 100 mA	V _F V _F	0.62	-	0.72 1	V V
Leakage Current at V_R = 20 V at V_R = 75 V at V_R = 20 V, T_j = 150 °C	I _R I _R I _R	_ _ _	_ _ _	25 5 50	nA μA μA
Capacitance at $V_F = V_R = 0$	C _{tot}	_	_	4	pF
Reverse Recovery Time from I_F = 10 mA to I_R = 1 mA, V_R = 6 V, R_L = 100 Ω	t _{rr}	_	_	4	ns
Thermal Resistance Junction to Ambient Air	R _{thJA}	_	_	0.351)	K/mW
Rectification Efficiency at f = 100 MHz, V _{RF} = 2 V	ην	0.45	_	_	_

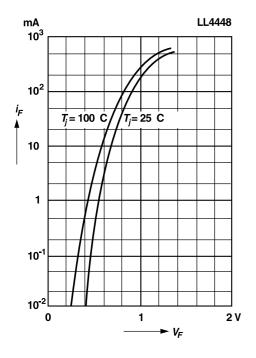
¹⁾ Valid provided that electrodes are kept at ambient temperature.



Rectification Efficiency Measurement Circuit

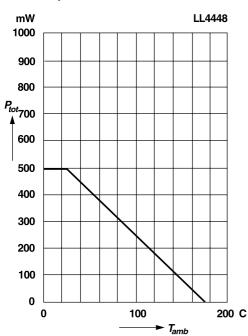
RATINGS AND CHARACTERISTIC CURVES LL4448

Forward characteristics

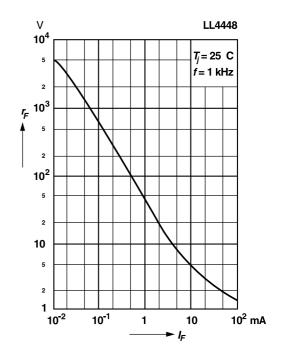


Admissible power dissipation versus ambient temperature

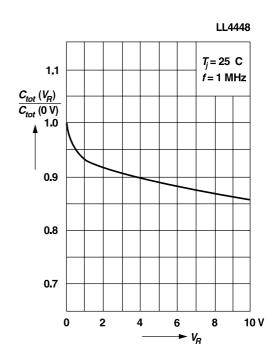
Valid provided that electrodes are kept at ambient temperature



Dynamic forward resistance versus forward current

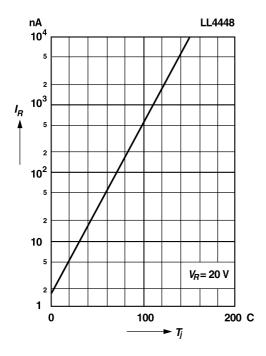


Relative capacitance versus reverse voltage



RATINGS AND CHARACTERISTIC CURVES LL4448

Leakage current versus junction temperature



Admissible repetitive peak forward current versus pulse duration

Valid provided that electrodes are kept at ambient temperature

